374. Title:Quantitative analysis and measurements of near-field interactions in terahertz microscopes
Authors:Moon, Kiwon (1); Jung, Euna (1); Lim, Meehyun (1); Do, Youngwoong (1); Han, Haewook (1)
Source title:Optics Express
Volume:19
Issue:12
Issue date:June 6, 2011
Publication year:2011
Pages:11539-11544
Language:English
Document type:Journal article (JA)
Abstract:We demonstrated quantitative analysis and measurements of near-fields interactions in a terahertz pulse near-field microscope. We developed a self-consistent line dipole image method

terahertz pulse near-field microscope. We developed a self-consistent line dipole image method for the quantitative analysis of the near-field interaction in THz scattering-type scanning optical microscopes. The measurements of approach curves and relative contrasts on gold and silicon substrates were in excellent agreement with calculations.